

FORM PTO 1449 (modified)		ATTY DOCKET NO. 00862.022498.		APPLICATION NO. 10/059,144	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		APPLICANT, TAKAO YONEHARA, ET AL.			
		FILING DATE January 31, 2002		GROUP 2823	
U.S. PATENT DOCUMENTS					
	DOCUMENT NUMBER	DATE	NAME	CLASS	FILING DATE IF APPROPRIATE
BU	5,757,456	05/26/98	Yamazaki, et al.	349	151
BU	6,627,487	09/30/03	Zhang	438	166
BU	6,682,963	01/27/04	Ishikawa	438	149
					
					
					
					
					
FOREIGN PATENT DOCUMENTS					
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	TRANSLATION YES/NO/ OR ABSTRACT
					
					
					
					
					
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)					
					
					
					
					
EXAMINER <u>Brown Kikade</u>					
DATE CONSIDERED <u>8/19/2004</u>					

AUG 19 2002

PRIORITY DOCKET NO. 00862.022498

APPLICATION NO. 10/059,144

LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

APPLICANT TAKAO YONEHARA, et al.

FILING DATE January 31, 2002

GROUP 2812

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Bu		6,190,937	02/20/2001	Nauagawa, et al.	438	67	
Bu		6,222,513	03/10/1998	Howard, et al.	345	84	
Bu		6,258,698	07/10/2001	Iwasaki, et al.	438	455	
Bu		6,306,729	10/23/2001	Sauaguchi, et al.	438	458	
Bu		6,331,208	12/18/2001	Nishida, et al.	117	89	
Bu		6,342,433	01/29/2002	Ohmi, et al.	438	455	
Bu		6,382,292	05/07/2002	Ohmi, et al.	156	584	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
Bu	EP	1 122 794	08/08/2001	Europe			
Bu	EP	858 110	08/12/1998	Europe			
Bu	EP	849 788	06/24/1998	Europe			
Bu	JP	11-316397	11/16/1999	Japan	G02F		Abstract

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

Bu		Shimoda, T., et al, "Surface Free Technology By Laser Annealing (SUFTLA)" International Electron Devices Meeting 1999. IEDM. Technical Digest. Washington, DC, Dec. 5 to 8, 1999, New York, NY: IEEE, US, August 1, 1999 (1999-08-01), pages 289 to 292, XP000933199 ISBN: 0-7803-5411-7.

EXAMINER BROOK KISHIDA

DATE CONSIDERED 8/19/2004

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.